

<b>Notice of References Cited</b>	Application/Control No. 10/077,778	Applicant(s)/Patent Under Reexamination HIGUCHI ET AL.	
	Examiner Brian R. Peugh	Art Unit 2187	Page 1 of 1

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	C	US-6,279,072	08-2001	Williams et al.	711/105
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**NON-PATENT DOCUMENTS**

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	U	Tanzawa et al., "A Compact On-Chip ECC for Low Cost Flash Memories", © 1997 IEEE, p. 662-668.
	V	Stassinopoulos et al., "Multiple Upset in Memories & Their Impact on Error Predictions and Sybsystem Designs", © 1992 IEEE p. 519-525.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.